Extended ROM Resident Diagnostics

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Preface

This manual describes rdg, the Solbourne Computer, Inc., ROM-resident diagnostics program. This manual is divided into four sections and an appendix, as follows:

- Section 1 Introduction This section introduces the Bootable/Standalone Diagnostics program rdg.
- Section 2 Getting Started with rdg This section explains how to begin using rdg.
- Section 3 rdg Tests This section presents the tests currently available using rdg.
- Section 4 Commands This section gives the user commands available when using rdg.
- Appendix A MARCH Algorithm This appendix gives an explaination of how the MARCH algorithm works.
- Appendix B Moving Inversions Test Algorithm
 - This appendix gives an explaination of how the moving inversions algorithm works.



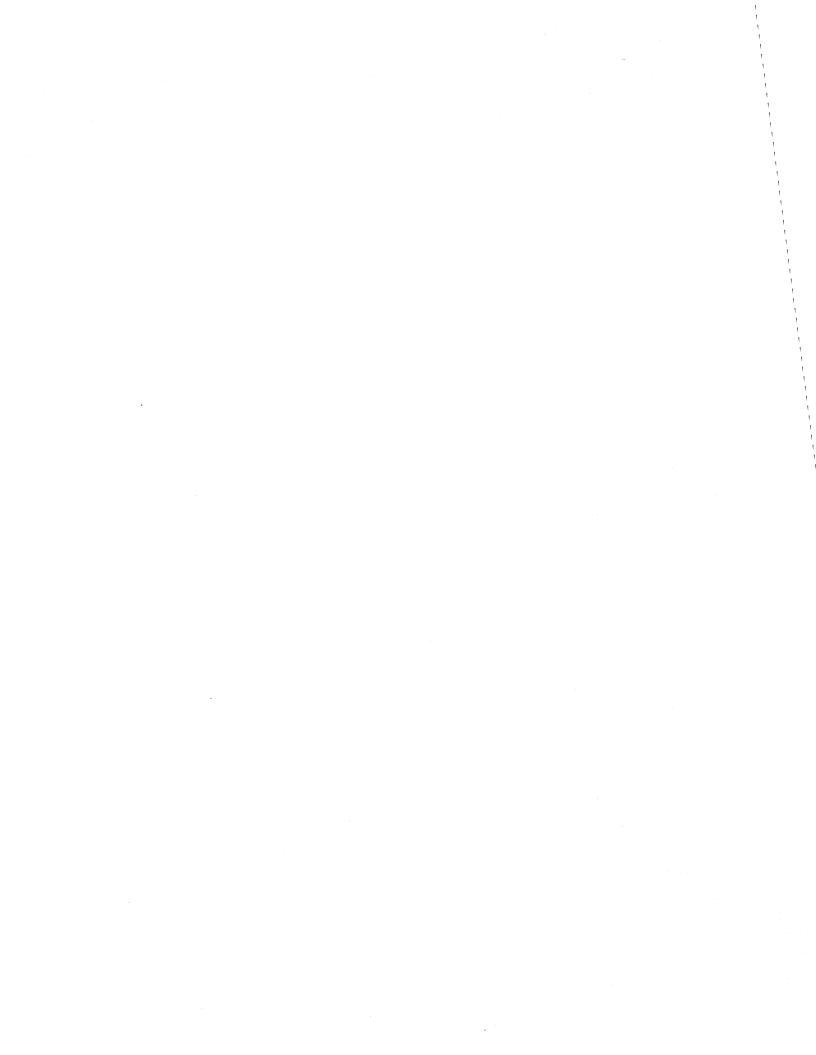
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Section 1: Introduction

1.1 Introduction

rdg is a ROM-resident diagnostics program. It is used to determine why a Solbourne system will not boot, if problems are encountered while booting the system. This program is for use primarily by engineering personnel.

The software for rdg includes:

- the rdg ROM-resident diagnostics program (rdg (1))
- test control commands
- rdg tests

1.2 Related Documentation

Information that may be useful while using the **rdg** program is available in the following documentation:

- Series4/600 Service Manual, Part number 101249-AA
- Series4/600 Theory Manual, Part number 101250-AA
- Series4/500 Service Manual, Part number 102161-AA
- Bootable/Standalone Multiprocessor Diagnostics Manual, Part number 101686-AB
- Bootable/Standalone Diagnostics Manual, Part number 101490-AB
- System Power On Self Test Manual, Part number 101486-AB

Section 2: Getting Started with rdg

2.1 Introduction

This section gives step-by-step instructions and examples for getting started using rdg.

In this section, commands you enter are given in **boldface** type. Command parameters for which you substitute a value are given in *italic*.

2.2 Invoking the rdg Program

The steps to follow the first time **rdg** is invoked are given below.

The user must first bring the Solbourne system to the **ROM>** prompt. If UNIX is running, it must be shutdown using the halt (1) command.

1. At the ROM> prompt, type:

ROM>rdg

2. When rdg is invoked, the RDG> prompt is displayed. There is no startup message.

When **rdg** is invoked the following values are given:

- The memory configuration table and memory limits are initialized with the values found by the ROM during the self-test.
- The frame buffer configuration table is initialized with the values found by the ROM during the self-test and the default frame buffer defaults to the frame buffer in the highest numbered slot.
- The VMEbus table comes up as empty.

2.3 Entering Commands to the rdg Prompt

rdg accepts input when the

RDG>

prompt is displayed.

Commands and parameters are case insensitive.

Other rules for entering commands include:

• In general more than one command can be entered in a single command line to the RDG> prompt at the same time.

RDG> tests 1 2 3 names on passlim 0 between 5 run

The above command line selects tests 1, 2, and 3, turns the printing of test names on, sets the pass limit to 0 (no passlim), the between count is set to 5, and begins test execution with the run command.

• Commands that process user input in an interactive mode, such as the **vmeconfig**(1) and **fbconfig**(1), cause commands that follow on the command line to be ignored.

- Commands must be separated by white space(s), including tabs or spaces. (Semicolons are not recognized by rdg as spaces.)
- If any of the command(s) entered return an error condition, all following commands are ignored and the RDG> prompt is redisplayed.
- If a command is unrecognized by rdg, the following is displayed:

Unknown command (command name)

- All command lines are terminated by a **Return**.
- Some commands may display additional error messages if numeric values are entered incorrectly or if the numeric values are not legal. These messages identify the value that is out of range, for example

illegal address (value given)

If an illegal value is given, additional information may be displayed that identifies the legal range of values.

- Memory and I/O addresses and contents must be entered in hexidecimal format. Any value that has to do with hardware must also be entered in hexidecimal (e.g., register data, memory address, or memory data).
- Counters and test numbers should be entered in decimal format (e.g., counts and limits).
- The rdg help(1) command can be used any time the RDG> prompt is displayed. A summary of the command given as an argument to help will be displayed.

2.4 Using rdg Commands

Example usage of each rdg command is given in Section 4 of this manual. All commands can be used with any other commands. All the rdg commands are for test control.

The test control commands are commands so categorized because they cause execution or alter the execution of the test programs.

2.4.1 Test Control Commands

The test control commands allow users to control tests run by rdg. The command names and their functions follow:

- between (1) Set or display between count
- config(1) Display memory configuration file
- continue(1) Set or display continue on error flag
- errlim (1) Set or display error limit
- errors (1) Display error count
- fbconfig (1) Generates (or modifies) the frame buffer configuration file
- help (1) Display a summary of the command given as an argument to help
- limit (1) Display or set memory test limits
- loop (1) Set or display loop on test flag

- menu (1) Display listing of available tests
- names (1) Enable or disable printing of test names during test execution
- next(1) Execute next selected test
- passes (1) Display pass count
- passlim (1) Set or display pass limit
- prompt(1) Set or display prompt flags
- quiet(1) Set or display error message enable flag
- quit(1) Exit from rdg debugger program
- restart (1) Restart execution of selected tests
- run(1) Start execution of selected tests
- status (1) Display or reset state of modes, flags, and counts
- tests (1) Select or display tests to be executed
- time (1) Set or display time flag and print current time and date
- vmeconf (1) Configure VMEbus devices

2.5 Starting Test Execution

By default, when **rdg** is invoked all the tests are selected. Tests are executed when the **run**(1) command is entered at the command line. For example:

RDG> tests run

If the tests command is entered without an argument, all the selected tests are displayed. For example:

RDG> **tests** selected tests: 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16

The test selection can be modified at any time the RDG> prompt is displayed. For example:

```
RDG> tests 9 8 4
RDG> tests
selected tests: 9 8 4
RDG>
```

The **menu** command identifies the test names or their functions. For example

```
RDG> menu
Menu of installed test programs:
Test 1: RTC-58321 real time clock test
Test 2: Memory Data RAM test (affected by prompt)
Test 3: Memory ECC RAM test (affected by prompt)
Test 4: VMEbus address map RAM test
Test 5: VMEbus data path test
Test 6: VMEbus address path test
Test 7: RF3500 SCSI data path (Write Buffer) test
Test 8: I/O ASIC register access test
Test 9: I/O ASIC FIFO/ECC test
Test 10: 7990 LANCE initialization test
Test 11: 7990 LANCE internal loopback test
Test 12: 7990 LANCE external loopback test (must be prompted)
Test 13: 33C93 SBIC (SCSI) enable test
Test 14: 33C93 SBIC (SCSI) data path (Write Buffer) test
Test 15: Ethernet tftp read test
Test 16: Disk write/read test
Test 17: Tape write/read test (must be prompted)
RDG>
```

For additional information on test execution, see the tests (1), run(1), and menu(1) commands in Section 4.

2.5.1 Variations of Test Execution

This subsection discusses some of the basic variations that can be applied to test commands. There are other variations than those given here.

Two results can occur during test execution. The test can pass or the test can fail.

If the test passes, the user can do any of the following:

- Tell the controller how many iterations to run using the passlim (1) command
- Controls whether the test names are printed using the names (1) command
- The user can also stop test execution at any time by entering a Control-C (^C)

If the test fails, the user can do any of the following:

- Set up a oscilloscope loop by using the loop (1) and quiet (1) commands
- Continue the failing test with the run command
- Skip to the next test in the selected sequence of tests using the next (1) command
- Restart the entire sequence using the restart (1) command.

2.6 Handling Test Failures

Several of the commands given in Section 2.4.1 that are used for test control can be used when test failures occur. In the following example, test 1 detects a failure and the loop and quiet commands are used to set up a scope loop.

```
RDG> tests 2 run
Starting Test 2: Memory Data RAM Test (affected by prompt)
TEST 2 ERROR: Thu Dec 1 10:03:05 1988
Error occurred in data ram memory test
Error code = 0xe0 Virtual addr = 0x00800000
Physical addr = 0x00ea0000 Board slot = 2
A data failure was found in the second read on the reverse pass.
exp = 0x5555555
act = 0x5555555
act = 0x0000008
RDG>
```

Note that test 2 has displayed its error message which identified the failing test case and returned to the RDG> prompt. If the user wishes to evaluate this test failure by setting up a scope loop, the sequence of commands shown in the following illustration may be entered.

Note that test 1 has repeated the failing test case and has redisplayed the same error message. This suggests the presence of a solid failure. To speed up the loop and avoid having to reenter the run command, the sequence of commands in the following illustration may be entered.

RDG> **quiet on run** (No information is displayed while the test is looping when the **quiet** command is invoked.) **^C**

No information is displayed while the loop and quiet flags are set. The program is not hung. It

is executing in the tightest possible loop of the failing test case. A Control-C must be entered to halt the loop and return to the RDG> prompt.

☆ ☆ ☆ NOTE ☆ ☆ ☆

It is a common mistake to forget to reset the **loop** and **quiet** flags before restarting the test sequence. This causes the first test case in the first test to be executed in a tight loop. See the **loop** and **quiet** commands in Section 4 for additional information.

2.7 Exiting rdg

To exit rdg use the quit(1) command.

Section 3: rdg Tests

3.1 Introduction

This section explains the functionality of the tests shipped by Solbourne Computer for use with the rdg (1) debugger. These tests include:

- 1. RTC-58321 Real Time Clock Test
- 2. Memory Data RAM Test (affected by prompt)
- 3. Memory ECC RAM Test (affected by prompt)
- 4. VMEbus Address Map RAM Test
- 5. VMEbus Data Path Test
- 6. VMEbus Address Path Test
- 7. RF3500 SCSI Data Path (Write Buffer) Test
- 8. I/O ASIC Register Access Test
- 9. I/O ASIC FIFO/ECC Test
- 10. 7990 LANCE Initialization Test
- 11. 7990 LANCE Internal Loopback Test
- 12. 7990 LANCE External Loopback Test (must be prompted)
- 13. 33C93 SBIC (SCSI) Enable Test
- 14. 33C93 SBIC (SCSI) Data Path (Write Buffer) Test
- 15. Ethernet tftp Read Test
- 16. Disk Write/Read Test
- 17. Tape Write/Read Test (must be prompted)

☆ ☆ ☆ NOTE ☆ ☆ ☆

Error messages from one test are not valid, if failures have occurred during previous tests. The errors from a test must be corrected before advancing to the next test.

3.2 RTC-58321 Real Time Clock Test

This test verifies that the real time clock (RTC) internal registers can be accessed and that the clock is counting. The chip used by the system is a RTC-58321. This is a slow bus chip that is located at RIO address 17020000.

This test consists of two parts:

- 1. Tests the RTC registers by writing test patterns and then reading them back for verification.
- 2. Tests verifies that writing the RTC chip can count by loading the registers such that a rollover causes a ripple from the least significant digit to the most significant digit.

Possible error messages follow:

```
RTC register write/read failure
RTC register address = RR
write pattern = P
exp = E
act = A
xor = X
where:
    RR - RTC register number
    P - pattern written to RTC register
    E - value expected to be read from RTC register
    A - actual value read from RTC register
    X - xor of expected and actual values
```

This error message implies that there may be a problem accessing the RTC chip from the slow bus.

```
Clock state rollover test failure (24 hr mode)

S MI HR W D MO YR

Initial state = 59 59 b2 6 31 12 99

Expected state = 04 00 80 0 01 01 00

Actual state = AA AA AA AA AA AA

where:

AA - actual state of RTC register
```

If this error occurs, an RTC chip failure has occurred.

3.3 Memory Data RAM Test (affected by prompt)

This test is an extended version of the ROM power-up self-test Addressing and Data Test. The test program performs a moving inverse test algorithm to verify the addressing and data paths (see the Appendix B for information on the moving inverse test algorithm).

The test program determines the test area from the Kbus memory limit entry in the memory limit table (refer to the limit (1) command to modify the test area).

The total test area is blocked into eight megabytes or less blocks.

During the read-write-read sequence, the target memory block is cached and checked for correct data. The data in the cache is then complemented and the block is flushed back to memory. The target block is then re-read and verified to contain the complemented data.

Legal error codes for the Data RAM Test are:

- 0x00 Data fault exception occurred during write of memory with initial data pattern
- 0x10 Data fault exception occurred during flush of a memory block on write of memory with initial data pattern
- 0x20 Data fault exception occurred on first read of forward pass
- 0x80 Data miscompare occurred on first read on forward pass
- 0x30 Data fault exception occurred during flush of target memory block back to memory during forward pass
- 0x40 Data fault exception occurred on second read of forward pass
- 0xa0 Data miscompare occurred on second read on forward pass
- 0x50 Data fault exception occurred on first read of reverse pass
- 0xc0 Data miscompare occurred on first read on reverse pass
- 0x60 Data fault exception occurred during flush of target memory block back to memory during reverse pass
- 0x70 Data fault exception occurred on second read of reverse pass
- 0xe0 Data miscompare occurred on second read on reverse pass

An example of a Data RAM Test failure follows:

```
Error occurred in data RAM memory test
Error code = 0xe0 Virtual addr = 0x00800000
Physical addr = 0x00ea0000 Board slot = 2
A data failure was found in the second read on the reverse pass.
exp = 0x55555555
act = 0x55555555
xor = 0x0000008
```

3.4 Memory ECC RAM Test (affected by prompt)

The test is an extended version of the ROM power-up self-test Addressing and Data Test. The test program performs a moving inverse test algorithm to verify the addressing and data paths (see Appendix A for information on the moving inverse test algorithm).

The Error Correction Code (ECC) test uses double word stores and loads to/from memory, the data RAM test uses word.

The test program determines the test area from the Kbus memory limit entry in the memory limit table (refer to the limit (1) command to modify the test area).

The total test area is blocked into 8 megabyte or less blocks.

During the read-write-read sequence, the target memory block is cached and checked for correct data. The data in the cache is then complemented and the block is flushed back to memory. The target block is then re-read and verified to contain the complemented data.

Legal error codes for the ECC test are:

- 0x00 Data fault exception occurred during write of memory with initial data pattern
- 0x10 Data fault exception occurred during flush of a memory block on write of memory with initial data pattern
- 0x20 Data fault exception occurred on first read of forward pass
- 0x80 Data miscompare occurred on high word in first read on forward pass
- 0x90 Data miscompare occurred on low word in first read on forward pass
- 0x30 Data fault exception occurred during flush of target memory block back to memory during forward pass
- 0x40 Data fault exception occurred on second read of forward pass
- 0xa0 Data miscompare occurred on high word in second read on forward pass
- 0xb0 Data miscompare occurred on low word in second read on forward pass
- 0x50 Data fault exception occurred on first read of reverse pass
- 0xc0 Data miscompare occurred on high word in first read on reverse pass
- 0xd0 Data miscompare occurred on low word in first read on reverse pass
- 0x60 Data fault exception occurred during flush of target memory block back to memory during reverse pass
- 0x70 Data fault exception occurred on second read of reverse pass
- 0xe0 Data miscompare occurred on high word in second read on reverse pass
- 0xf0 Data miscompare occurred on low word in second read on reverse pass

An example of an ECC test failure follows:

```
Error occurred in ECC RAM memory test
Error code = 0x40 Virtual addr = 0x00800000
Physical addr = 0x00ea0000 Board slot = 2
An exception occurred after re-read of a double on the forward pass
Exception type = data fault, FCR = 0x02, Syndrome = 0x00
```

3.5 VMEbus Address Map RAM Test

This test verifies that the VMEbus address map RAM on the System Board is accessible via RIO transactions. It does not verify that Kbus/VMEbus address translations can be performed.

The VMEbus map RAM is a 2048 word memory and is accessible at low address 83000000 and high address 83ffe000. The adjacent locations in the RAM are at 2000 hexadecimal increments.

Strategy: Write random byte sequence to 2048 VMEbus map RAM locations. Read and verify contents of VMEbus map RAM.

Possible error messages follow:

```
VMEbus address map write/read error
RIO address = 0xYYYYYYY
exp = EEEEEEEE
act = AAAAAAAA
xor = XXXXXXXX
where:
    YYYYYYYY - RIO address where error occurred
    EEEEEEEE - value expected to be read from address
    AAAAAAAA - actual value read from address
    XXXXXXXX - xor of expected and actual values
```

If this test fails, the control logic for accessing the RAM should be checked to be functional. If the control logic is operational, then insure the RAM chips are receiving address and data correctly.

3.6 VMEbus Data Path Test

This test verifies correct data path access to the VMEbus using RIO cycles. Note that a VMEbus resident RAM Board must be installed and configured using the **vmeconfig**(1) command. This test requires a VMEbus Memory Board installed in the VMEbus backplane and the boards' presence listed in the VMEbus configuration table (see the command 'vmeconfig' for more information).

The test program writes and reads the VMEbus RAM Board as a 16 bit device and an 8 bit device. The 8 bit device test verifies that the correct VMEbus data strobe line is used and that the unused data strobe does not. The test is run for each data strobe line.

```
VMEbus data error, 16 bit accesses
address = 0x86100000
act = 0xfffe
exp = 0xffff
xor = 0x0001
VMEbus data error, 8 bit accesses
address = 0x86100000
act = 0xff02
exp = 0xff00
xor = 0x0002
```

3.7 VMEbus Address Path Test

This test verifies that address lines on the VMEbus backplane do not interact with each other. Note that a VMEbus resident RAM Board must be installed and configured using the vmeconfig (1) command. This test requires a VMEbus Memory Board installed in the VMEbus backplane and the boards' presence listed in the VMEbus configuration table (see the vmeconfig (1) command for more information).

The test writes and reads the VMEbus RAM Board as a 16 bit device. The test program sets the entire VMEbus ram to 0x0000, then each single bit address line is set to 0xffff. For example:

address	contents
0×0000000	0x000x0
0x000002	0xffff
0x000004	0xffff
0x000006	0x0000
0x000008	0xffff
0x00000a	0x0000
0x00000c	0x0000
0x00000e	0x0000
0x000010	0xffff
0x000012	0x000x0
•	•
•	•
0x0fffff	0x0000

In this way any address line that interacts with another one will write the opposite data to the location.

The test is repeated using a single low bit in the address.

```
VMEbus addressing error
address = 0x86100000
act = 0xffff
exp = 0x0000
```

3.8 RF3500 SCSI Data Path (Write Buffer) Test

This test verifies functionality of the VMEbus emulator on the System Board and the connection of the SCSI device to the Ciprico RIMFIRE 3500 SCSI (Ciprico) Board.

This test requires a Ciprico VMEbus SCSI Board installed in the VMEbus backplane and the boards' presence listed in the VMEbus configuration table (see the command 'vmeconfig' for more information).

The test sequence follows:

- 1. The Ciprico SCSI Board is reset and the test waits for the board to complete self tests.
- 2. The board options are set with a SCSI id of 7.

- 3. The unit options are set with a retry limit of 3.
- 4. The test waits for a minimum of 5 seconds to allow the device to recover from the SCSI bus reset.
- 5. The test performs a SCSI TEST UNIT READY command. This first command will fail with a check condition status and a sense key of 0x06. This error is expected, it is the drive saying it was reset.
- 6. The size of the devices buffer is queried and is used for the transfer count. This count is displayed.
- 7. The data to transfer to the device is set up, an incrementing pattern is used.
- 8. The data is transferred to the device using the SCSI WRITE BUFFER command.
- 9. The data is transferred from the device using the SCSI READ BUFFER command.
- 10. The data read is verified to be the same data that was sent.
- 11. The data transfer, write-read-verify sequence, is repeated when loop is on.

An example of a data failure follows:

```
Data error on SCSI transfer
transfer offset = 350
exp = 0x02
act = 0x03
xor = 0x01
```

Errors in this test can be from:

- The System Board will not address the Ciprico SCSI (run VMEbus Data and Address path tests to verify).
- The System Board will not allow the Ciprico Board to address system RAM (run System Board VMEbus address map RAM test to verify mapping RAM). This is not the only cause for this condition.
- The 'Error on first selection of device' error specifies that SCSI device address 0 and Logical Unit Number (LUN) 0 could not be selected. Verify the device:
 - 1. cables are not damaged and connected
 - 2. is addressed as device 0
 - 3. is addressed as LUN 0

SCSI errors return the command that was issued and the device that was addressed. The commands used are shown in the following table.

Command	Device	Description
0x00	0x00	SCSI command, TEST UNIT READY
0x07	0xff	Ciprico Board command, set general options
0x07	0xff	Ciprico Board command, set device options
0x3b	0x00	SCSI command, WRITE BUFFER
0x3c	0x00	SCSI command, READ BUFFER

Errors returned from the device will display Ciprico Board error status (error code) and various SCSI status bytes. Refer to the Ciprico RIMFIRE 3500 Product specification and the Small Computer Systems Interface specification for further information.

Example of an error on a command follows:

```
Error status returned after command
error code = 0x4b SCSI status = 0x02 SCSI flags = 0x00
info byte 3 = 0x00 4 = 0x00 5 = 0x00 6 = 0x00
Command 0x3c on device 0x00
```

3.9 I/O ASIC Register Access Test

This test verifies that the I/O ASIC will retain data in internal registers and verify the access to the Western Digital (33C93) SCSI Bus Interface Controller (SBIC) and the AMD 7990 Local Area Network Controller for Ethernet (LANCE) chips. Refer to the technical manuals of these devices for additional information.

For each test, the invlid bits are masked before comparing data.

The first part of this test checks all I/O ASIC registers for data retention. Each register has a series of patterns written, read back and verified.

```
Data error in Ethernet receive address register
exp = 0x00000000
act = 0x00000040
```

The test continues by verifying that each of the I/O ASIC's five (5) read/write rergisters are unique. The test sequence for this test is as follows:

```
clear all registers
writing the test register to all ones
check all for proper data
write all registers to all ones
clear the test register
check all for proper data
```

The above example is repeated for all registers as the test register.

```
Data retention error in test register
test register = Ethernet receive address register
   exp = 0x0001ffff
   act = 0x0001ffef
```

In the above example, the test registers did not retain the value written to it.

```
Addressing error on ASIC
test register = SCSI DMA address register
value written = 0x00000000
register modified = SCSI control/address register
exp = 0x00007ffd
act = 0x00000000
```

In the above example, writing to the SCSI DMA address register caused the SCSI control/address register to be modified.

The next two tests verify accessability and data retention of the AMD 7990 LANCE chip and the WD 33C93 SBIC chip. Each device is presented a pattern and read back. The LANCE has a 16 bit data bus and the 33C93 has an 8 bit.

The LANCE test uses CSR1 for the test.

```
Data retention error in LANCE chip
exp = 0xfffe
act = 0xfefe
```

The 33C93 test uses the total cylinders, low byte, register for the test.

```
Data retention error in SCSI chip
exp = 0x08
act = 0x00
```

3.10 I/O ASIC FIFO/ECC Test

This test verifies the I/O ASIC will fetch a cache block from KBus memory and that single bit errors in any cacheline will be corrected. Every data bit in every cache line is verified to be correctable. The test verifies the following conditions:

- 1. A zero bit corrected to a one in a field of zeroes
- 2. A one bit corrected to a zero in a field of ones
- 3. A one bit corrected to a zero in a field of zeroes
- 4. A zero bit corrected to a one in a field of ones

The LANCE chip is used to force the I/O ASIC to fetch the test cache block.

The cache block is written to memory with one cache line with bad data and good ECC. The I/O ASIC is forced to fetch the block and the cache block is read again. The data read is verified to be corrected.

In the above example, the I/O ASIC did not correct the bad bit in the cache line or it did not fetch the block.

3.11 7990 LANCE Initialization Test

This test verifies that the AMD 7990 LANCE chip can initialize through the I/O ASIC from Kbus memory. To verify the initialization, the LANCE status register is verified to contain the expected status.

Ignored bits are masked off.

```
LANCE initialization error
exp status = 0x0020
act status = 0x0030
mode value = 0x0002
```

In the above example, the LANCE chip received the wrong mode value.

Refer to the AMD 7990 technical manual for further information.

3.12 7990 LANCE Internal Loopback Test

This test verifies proper operation of the LANCE with the I/O ASIC, its' address registers and interrupts to the processor. The test initializes the LANCE for internal loopback mode and sets up a transmit packet of 32 bytes, the maximum for the LANCE, and transmits it to itself. The received packet is then verified.

The expected vector for the LANCE chip is 0x87. Interrupts are checked for valid on:

- 1. Initialization
- 2. Transmit packet
- 3. Receive packet

```
Unexpected interrupt active after LANCE initialization
No interrupts expected
vector received = 0x80
```

In the above example, a device that is not being tested generated an interrupt when the LANCE did something.

Data error o	n internal LANCE loopb	back	
addr	exp	act	xor
0x000c00c0	0x0001020304050607	0x0001020384050607	0x00000008 000000

In the above example, a bad bit was found in the I/O ASICs' Ethernet cacheable block buffer.

3.13 7990 LANCE External Loopback Test (must be prompted)

This test verifies the operation of the LANCE chip with the data encoding component's on the System Board.

An external loopback connector must be installed before this test is run. Figure 3-1 shows the pin layout for the transceiver connector.

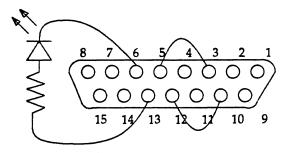


Figure 3-1. Pin Layout for Transceiver Connector on EXOS 202

```
Time out on LANCE transmit
LANCE status = 0x0033
```

In the above example, the external loopback connector is not connected or an external component is bad.

3.14 33C93 SBIC (SCSI) Enable Test

This test verifies the SCSI chip reset latch will hold the SCSI chip reset and release it from reset. The SCSI chip will not load a value into any register when it is reset. This is the indication that it is reset.

```
SBIC chip not reset after reset latch set
    exp = non zero
    act = 0x00
SBIC chip reset after reset latch reset or data error
    exp = 0x00
    act = 0xff
```

3.15 33C93 SBIC (SCSI) Data Path (Write Buffer) Test

This test verifies the operation of the WD 33C93 SBIC chip (SCSI) with the I/O ASIC.

The chip is set with a SCSI id of 7 (highest priority) and interrupts are verified to occur and be the correct vector.

The test sequence is as follows:

- The test waits for a minimum of 5 seconds to allow the device to recover from the SCSI bus reset.
- The test performs a SCSI TEST UNIT READY command. This first command will fail with a check condition status and a sense key of 0x06. This error is expected and accounted for, it is the drive saying it was reset.
- The data to transfer to the device is set up, an incrementing pattern of 512 bytes is used.
- The data is transferred to the device using the SCSI WRITE BUFFER command.
- The data is transferred from the device using the SCSI READ BUFFER command.
- The data read is verified to be the same data that was sent.

An example of a data failure follows:

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SCSI transfe	r error		
addr	exp	act	xor
0x000c0000	0x0001020304050607	0x0001020384050607	0x00000008 0000000

The "Timeout on access to target 0 after reset" error specifes that SCSI device address 0 and Logical Unit Number (LUN) 0 could not be selected. Verify the device:

- 1. Cables are not damaged and connected
- 2. Is addressed as device 0
- 3. Is addressed as LUN 0

SCSI errors return the command that was issued. The commands used are:

commanddevicedescription0x000x00SCSI command, TEST UNIT READY0x3b0x00SCSI command, WRITE BUFFER0x3c0x00SCSI command, READ BUFFER

Errors returned from the device will display:

- 1. SCSI status
- 2. Target status
- 3. Command phase
- 4. SBIC chips status (auxilliary status)

For example:

SCSI status	target status	command phase	auxilliary status
exp = 0x02	0x02	0x02	0x02
act = 0x02	0x02	0 x02	0x02

Please refer to the 33C93 Technical Reference and the the Small Computer Systems Interface (SCSI) specification for further information.

3.16 Ethernet TFTP Read Test

The Ethernet TFTP Read Test verifies the Solbourne workstation's ability to read a file from a host servers's file system.

The file system on the server must have a "/export/exec/kvm/series[45]/stand" directory which contains the "tftpread.data" file. The host server must also be set up to be a tftp file server. This means that the /etc/hosts and /etc/ethers file must contain entries which map the ethernet address of the workstation under test to its internet address.

The "DIAGSERVER" ROM environment variable on the Solbourne workstation under test must be set to accurately point to the directory containing tftpread.data on the server. For example, "DIAGSERVER = tftp.ex(,,1)/export/exec/kvm/series[45]/stand." tftp.ex is the name associated with the EXELAN ethernet device, tftp.ei is the name associated with the IOASIC ethernet device.

If the "DIAGSERVER" ROM environment variable is not set, the test will print:

```
Environment variable DIAGSERVER not initialized Test Skipped.
```

When the test attempts to open the file on the remote file system a "rarp" (reverse arp) operation is performed in which the workstation sends out its Ethernet address and the server responds by sending back the internet address of the requesting workstation along with the internet address of the responding server.

If the server fails to respond, a string of messages like the following will be seen as the driver keeps retrying the rarp using its ethernet address. If the server never responds, the rarp request will timeout.

```
rarp: requesting internet address for 8:0:14:20:38:92
rarp: timeout on request
```

If any of the above situations arise, the user should make sure that the server and workstation under test have been setup correctly and that all Ethernet cable connections are secure.

If the server responds normally, several "rarp" messages will be seen on the console:

```
rarp: using IP address 192.9.201.140 = C009C98C
rarp: server at IP address 192.9.201.27 = C009C91B
```

In the above messages, the first message represents IP address of the workstation and the second message represents the IP address of the responding server.

If the initial open of the file pointed to by the "DIAGSERVER" variable fails, the test will print the following message and halt.

If the file open is successful, the test reads the data packets sent from the server and compares the data with a re-generated copy of the data. If a read fails, the test will print the following message:

Where fd is the file descriptor returned from the file open operation and count is the number of bytes returned from the read call. The read operation always requests 4 bytes at a time.

If there are no errors returned from the read operation, the test compares the data read with expected data. If there is a data miscompare, the test will print the following messages and halt:

A data miscompare error indicates that the data stream was corrupted by the Ethernet device (EXELAN or ASIC) during the time it was received from the network cable and placed in system memory. In any case, the entire data path (cable, Ethernet device and System Board) should be suspect.

3.17 Disk Write/Read Test

The Disk write/read test verifies the ability of the Solbourne workstation to write data to a disk and read it back. The test is device independent in that it will run on any disk device supported by the standalone driver (SCSI or SMD).

The test performs 128 Kbyte writes and reads on the disk partition specified by the DEFAULTSWAP ROM environment variable. The DEFAULTSWAP variable must be valid for the test to operate correctly. In addition, incorrectly setting the DEFAULTSWAP device could result in corruption of disk data.

If the DEFAULTSWAP variable has not been initialized, the test will print the following message:

```
Environment variable DEFAULTSWAP not initialized
Test Skipped.
```

If the DEFAULTSWAP variable has been initialized. The test attempts to open the specified device. If the open fails for any reason, the test will print the following message and halt (assuming DEFAULTSWAP is set to sd.si(,,1):

Default swap device sd.si(,,1) cannot be opened

Once the specified disk device has been successfully opened, the test calls a driver function which returns the number of disk blocks associated with the specified partition. If the specified partition is of zero size, the test prints the following message and halts:

Null size for device partition sd.si(,,1)

If any of the above messages are displayed, the user should verify that the DEFAULTSWAP variable has been correctly set up and that the signal and power cableing on the target disk system is connected and intact.

Once passed the above checks, the test fills a 128 Kbyte block of physical memory with a repeating pattern of 0xb6d9, writes the data buffer to disk block 0 then reads the disk data back into another 128 Kbyte memory buffer.

If the call to the write function returns an error, the test will print the following message and halt:

```
Write Error: device sd.si(,,1), fd = 3, count = 0x0
target block = 0
block address = 0x00000000
transfer size = 0x00020000
write buffer = 0xff0c0000 - 0xff0dffff
```

After the disk write has been performed, the test zeroes out the buffer that will be used during the read, then reads the disk into the buffer.

```
Read Error: device sd.si(,,1), fd = 3, count = 0x0
target block = 0
block address = 0x00000000
transfer size = 0x00020000
read buffer = 0xfffe0000 - 0xffffffff
```

After the disk read has been completed, the test verifies that the write buffer data matches the read buffer data. If there is a data miscompare, the test will print the following message and halt:

```
Data Compare Error: device = sd.si(,,1), fd = 3
target block = 0
block address = 0x00000000
write buffer = 0xff0c0000 - 0xff0dffff
read buffer = 0xfffe0000 - 0xffffffff
error occurred at buffer offset 0x100
    expected: (0xff0c0100) = 0xb6
    actual: (0xfffe0100) = 0x00
```

3.18 Tape Write/Read Test (must be prompted)

The Tape write/read test verifies the ability of the Solbourne workstation to write data to a tape and read it back. The test is device independent in that it will run on any tape device supported by the standalone driver.

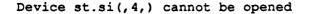
This test must be prompted in order to run. When the test is not prompted, the following message is printed:

Test 17 skipped - use PROMPT command to enable

If the test is prompted, the user is prompted for the following information:

```
Enter tape device name:
```

The user must enter the name of the device to test (assuming the user enters stsi(4,)). If the user enters "quit" the test will be halted, otherwise the test will attempt to open the specified device. If the open fails, the following message will be printed and the user will be prompted to specify another device name.



If the device is successfully opened, the user is asked to insert a scratch tape and enter return:

Please install a scratch tape and hit return when ready to continue

When the user enters return, the test writes random data patterns on the tape, reads them back and verifies that the data is correct.

When the disk test begins, the following message is printed:

Testing et. si (14,): Entre liansfue suge (defaults is 0x20000)

The test then begins the following operations:

it reduce

Л

```
Open the device for write
Write 128 Kbytes of random data patterns
Close the device
Open the device for read
Read the data back
Close the device
Verify the data
```

During the test, one of the following error messages could be displayed depending on the type of error (write, read, compare):

Load. Writing Closing Opining for used Reading Closurp Usufying.

```
Device st.si(,4,) cannot be opened for write
Write Error: device st.si(,4,), fd = 3, count = 0x0
target block = 36504
block address = 0x011d3000
transfer size = 0 \times 00003686
write buffer = 0xffc04840 - 0xffc07ec8
Device 'devicename' cannot be opened for read
Read Error: device st.si(,4,), fd = 3, count = 0x0
target block = 36504
block address = 0 \times 011d3000
transfer size = 0 \times 00003686
read buffer = 0xffa3a6fe - 0xffa3dd86
Data Compare Error: device st.si(,4,), fd = 3
target block = 36504
block address = 0x011d3000
transfer size = 0 \times 00003686
write buffer = 0xffc04840 - 0xffc07ec8
read buffer = 0xffa3a6fe - 0xffa3dd86
error occurred at buffer offset 0x0
  expected: (0xffc07ec8) = 0xd9
  actual: (0xffa3dd86) = 0x00
```



Section 4: Commands

4.1 Introduction

This section offers printed copies of man pages for all commands associated with rdg(1). The commands are presented in the UNIX man page reference format.

A summary of the command usage is displayed on-line when rdg is running by typing:

RDG> ?

The following is a listing of the **rdg** commands available in this section:

SECTION 1: COMMANDS

between(1) config(1) continue(1) errlim(1) errors(1) **fbcon**fig(1) help(1) limit(1) loop(1)menu(1) names(1) next(1) passes (1) passlim(1) prompt(1) quiet(1)quit(1)rdg(1)restart(1) **run**(1) status(1) tests (1) time (1) vmeconf(1)

between - Set or display between count

SYNOPSIS

between [count]

DESCRIPTION

between sets or displays the current setting of the between count. **between** suppresses printing test completed messages to the screen until *count* passes have completed.

When the status (1) reset command is used, the between count is reset to 1.

OPTION

count Specifies the number of test passes that must be completed before a completion message is displayed. By default the **between** *count* is always set to 1.

EXAMPLE

User input in the example is shown in **boldface** type.

The following example illustrates how to set and redisplay the **between** count.

```
RDG> between 4
RDG> between
Between count = 4
RDG>
```

SEE ALSO

rdg(1), passlim(1), status(1)

config - Display memory configuration file

SYNOPSIS

config

DESCRIPTION

config displays the memory configuration. When rdg is invoked it creates a memory configuration table based on the memory configuration information saved in the diagnostic RAM during the power-up self-tests.

EXAMPLES

User input in the examples is shown in **boldface** type.

In the following example, **config** is entered at the RDG prompt. The current contents of the configuration table are displayed.

```
RDG> config
Memory Configuration:
5 board(s) totaling 80 Mbytes
5 slot 1 16 Mbytes Base address = 00000000
5 slot 2 16 Mbytes Base address = 01000000
5 slot 3 16 Mbytes Base address = 02000000
5 slot 4 16 Mbytes Base address = 03000000
5 slot 5 16 Mbytes Base address = 04000000
```

RDG>

SEE ALSO

rdg(1)

continue - Set or display continue on error flag

SYNOPSIS

continue [on | off]

DESCRIPTION

continue sets or displays the continue-on-error flag. If no parameters are specified, continue displays the current setting of the continue-on-error flag.

The **continue** flag commands tests to continue executing after a test failure occurs. Tests are designed to check the continue flag to determine if test execution should be halted (the default condition) or if the next test case should be executed.

OPTIONS

- on Turns on the continue-on-error flag.
- off Turns off the continue-on-error flag.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example causes the current error message enable flag to be displayed.

```
RDG> continue
continue = off
RDG>
```

The following example illustrates how the continue flag is changed and redisplayed.

```
RDG> continue on
RDG> continue
continue = on
RDG>
```

SEE ALSO

rdg(1), **status**(1)

errlim - Set or display error limit

SYNOPSIS

errlim [limit]

DESCRIPTION

errlim sets or displays the current setting of the test error limit.

OPTION

limit Specifies the number of test errors that can occur before test execution is halted. By default, the *limit* is set to zero (no error limit). However, the error limit may be changed by specifying a new limit value. The limit value must be entered in unsigned decimal format and be between 0 and 2,147,483,647, inclusive.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example illustrates how to display the current error limit.

```
RDG> errlim
Error limit = 0
RDG>
```

The following example illustrates how to change and re-display the error limit.

```
RDG> errlim 100
RDG> errlim
Error limit = 100
RDG>
```

SEE ALSO

rdg(1), errors(1), status(1)

errors - Display error count

SYNOPSIS

errors

DESCRIPTION

errors displays the number of test errors that have occurred since the last run(1) command.

EXAMPLE

User input in the example is shown in **boldface** type.

The following example illustrates how to display the error count.

RDG> **errors** Total test errors = 0 RDG>

SEE ALSO

errlim(1), rdg(1), status(1)

fbconfig - **displays** the frame buffer configuration file

SYNOPSIS

fbconfig

DESCRIPTION

The frame buffer configuration is read from the diagnostic RAM when **rdg** is invoked. The boards must be configured in descending slot order.

EXAMPLE

User input in the example is shown in **boldface** type.

RDG> fbconfig

Frame Buffer Configuration:

1 graphics board(s): Slot IO address Board Type Resolution 1 81000000 monochrome low Slot number of default board to test: 1 RDG>

SEE ALSO

rdg(1)

help - Display this command list or information on a specific command

SYNOPSIS

help [command ...]

DESCRIPTION

The help command with no arguments causes a list of command and command usages to be displayed. This is equivalent to the ? command.

The help command with an argument causes the command usage for the specified command to be displayed.

OPTIONS

command

name of command for which help is desired.

EXAMPLE

The following example causes the command usage for the tests command to be displayed:

```
RDG> help tests
        Usage: tests [ all | test ... | test:test ... ]
RDG>
```

SEE ALSO

rdg(1)

limit - Display or set memory test limits

SYNOPSIS

limit[reset | memname[low high | reset]]

DESCRIPTION

limit displays or sets the memory test limits of the system. By default, limit displays all the memory limits.

limit is set to the amount of installed memory for each memory devices in the system. Memory devices include physical memory, VMEbus address map memory, and VMEbus resident memory boards.

The test programs examine the memory limits to determine how much memory to test.

OPTION

reset Resets the limits back to the default settings. The default settings are determined by the amount of installed memory. For example, as set by the config (1) command.

low high

low is the first address and high is the last address to test, inclusive.

EXAMPLE

User input in the example is shown in **boldface** type.

The following example displays the current limit settings for all the memory devices.

RDG> limit		
Memory limits:	LOW	HIGH
mem =	5fff	8fff
vmemap =	40	7ff
vmemem =	3	5ff

The following example resets the memory limits to their default values.

RDG> limit r	eset		
RDG> limit			
Memory limit	s:	LOW	HIGH
mem	=	40000	lfffff
vmemap	-	20	7ff
vmemem	=	0	7fff

The following example sets the memory limits for physical memory to the range 40000 through 2ffffff hex and sets the VMEbus address map limits to 20 through ff hex, inclusive.

RDG> limit mem 4	0000 2ff	Efff
RDG> limit vmema	ap 20 ff	
RDG> limit		
Memory limits:	LOW	HIGH
mem =	40000	2ffff
vmemap =	20	ff
vmemem =	0	7fff

The following example resets only the VMEbus address map limits to their default values. The physical memory values are not modified.

RDG> limit v	memap	reset	
RDG> limit			
Memory limit	s:	LOW	HIGH
mem	=	40000	2fffff
vmemap	=	20	7ff
vmemem	=	3	5ff

RDG>

SEE ALSO

config(1), rdg(1)

loop - Set or display loop on test flag

SYNOPSIS

loop [on | off]

DESCRIPTION

loop sets or displays the loop on error flag. If no parameters are specified, **loop** displays the current setting of the loop flag.

The loop flag commands tests to loop on the failing test case in the event a test error occurs. Tests are designed to halt when errors occur so that the loop command may be entered.

OPTIONS

on Turns on the loop flag.

off Turns off the loop flag.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example causes the current loop flag do be displayed.

RDG> **loop** loop = off RDG>

The following example illustrates how the loop flag is changed and re-displayed.

```
RDG> loop on
RDG> loop
loop = on
RDG>
```

SEE ALSO

rdg(1), status(1)

menu - Display listing of available tests

SYNOPSIS

menu

DESCRIPTION

menu lists the names of all available tests in the default order of execution. **menu** displays tests in the default order of execution.

EXAMPLE

User input in the example is shown in **boldface** type.

The following example displays the list of installed tests.

```
RDG> menu
RDG> menu
Test 1: RTC-58321 real time clock test
Test 2: Memory Data RAM test (affected by prompt)
Test 3: Memory ECC RAM test (affected by prompt)
Test 4: VMEbus address map RAM test
Test 5: VMEbus data path test
Test 6: VMEbus address path test
Test 7: RF3500 SCSI data path (Write Buffer) test
Test 8: I/O ASIC register access test
Test 9: I/O ASIC FIFO/ECC test
Test 10: 7990 LANCE initialization test
Test 11: 7990 LANCE internal loopback test
Test 12: 7990 LANCE external loopback test (must be prompted)
Test 13: 33C93 SBIC (SCSI) enable test
Test 14: 33C93 SBIC (SCSI) data path (Write Buffer) test
Test 15: Ethernet tftp read test
Test 16: Disk write/read test
Test 17: Tape write/read test (must be prompted)
RDG>
```

SEE ALSO

rdg(1), tests(1)

names - Enable or disable printing of test names during test execution

SYNOPSIS

names [on | off]

DESCRIPTION

names enables or disables the printing of test names during test execution.

OPTIONS

- on Enables the printing of the test names during test execution. This is the default setting.
- off Disables the printing of the test names during test execution.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example causes the state of the name flag to be displayed.

RDG> **names** names = on RDG>

The following example illustrates how the names flag is changed and redisplayed.

```
RDG> names off
RDG> names
names = off
RDG>
```

SEE ALSO

rdg(1), status(1)

next - Execute next selected test

SYNOPSIS

next

DESCRIPTION

next causes the test sequence to be continued, starting with the next selected test. It is used when a test halts on an error and the user wishes to continue test execution with the next test in the sequence.

EXAMPLE

User input in the example is shown in **boldface** type.

In the following example run was entered to begin test execution. The current test selection was executed until an error was encountered in test 3. next was entered to continue the test sequence starting with the next test in the sequence.

١

RDG> run					
Starting	Test	1:	(testname	e)	
Starting	Test	2:	(testname	e)	
Starting	Test	3:	(testname	∋)	
Test 3 er	cror:	(e1	ror mess	age)	
RDG> next	t				
Starting	Test	4:	(testname	e)	
Starting	Test	5:	(testname	e)	
Starting	Test	6:	(testname	e)	
•					
•					
•					
Starting	Test	n:	(testnam	e)	
Tests cor	nplete	ed:	Passes =	1 Errors	= 1 \
				15:41:29	
RDG>			•		

SEE ALSO

between (1), errlim (1), passlim (1), rdg (1), restart (1), run (1)

passes - Display pass count

SYNOPSIS

passes

DESCRIPTION

passes displays the number of complete test passes that have made since the last run command.

EXAMPLE

User input in the example is shown in **boldface** type.

The following example illustrates how to use the **passes** command.

RDG> **passes** Total passes = 0 RDG>

SEE ALSO

passlim(1), rdg(1)

passlim - Set or display pass limit

SYNOPSIS

passlim [limit]

DESCRIPTION

passlim sets or displays the current setting of the test pass *limit*. **passlim** specifies the number of test passes that can occur before test execution is halted.

This command should be used when it is desired to execute numerous passes of the test sequence.

OPTION

limit Sets the number of test passes that will be run. By default, *limit* is set to one. *Limit* must be entered in unsigned decimal format in the range 0-to-2,147,483,647, inclusive. A *limit* of 0 specifies that tests execute continuously until a Control-C is entered.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example illustrates how to display the current pass limit.

```
RDG> passlim
Pass limit = 1
RDG>
```

The following example illustrates how to change and re-display the pass limit.

```
RDG> passlim 0
RDG> passlim
Pass limit = 0
RDG>
```

SEE ALSO

passes (1), rdg(1)

prompt - Set or display prompt flags

SYNOPSIS

prompt[all | off | test test ... | test:test ...]

DESCRIPTION

prompt sets or displays the prompt flag for each test program. The command allows the user to selectively alter the default behavior of the test programs by turning the flag for the specified tests on or off.

Only a few of the rdg tests use the prompt flag. The behavior of the test depends on what the test is attempting to accomplish. In some case, if a test isn't prompted it does not execute. In others, it modifies the test algorithm.

Single tests or a range of tests may be prompted by specifying the test numbers or range of tests number.

The menu (1) command indicates which tests examine their prompt flags.

OPTIONS

- **all** Set prompt flags for all tests. **all** can be specified at any time to prompt all tests.
- off Turns prompt flags for all tests off. off can be specified at any time to turn off prompts/for all tests.
- *test* Prompt specified *test*. If *test* is not specified, the **prompt** command displays the current status of the **prompt** flags.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example illustrates how to display the prompt flags.

RDG> prompt no prompted tests RDG> prompt all RDG> prompt						
prompted tests: 1	2	3	4	5	6	7
8	9	10	11	12	13	14
15	16	17				
RDG> prompt off RDG> prompt 8 9 10 RDG> prompt prompted tests: 8	9	10				

SEE ALSO

menu (1), rdg (1), tests (1)

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quiet - Set or display error message enable flag

SYNOPSIS

quiet[on | off]

DESCRIPTION

quiet sets or displays the error message enable flag. If no parameters are specified, **quiet** displays the current setting of the flag.

The error message enable flag prevents error messages from being displayed on test failures. This feature should be used to create the tightest possible loop when the loop flag is on. A Control-C must be entered to stop the loop and return to the RDG> prompt.

OPTIONS

on Turns on the quiet flag.

off Turns off the quiet flag.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example causes the current error message enable flag to be displayed.

RDG> **quiet** quiet = off RDG>

The following example illustrates how the quiet flag is changed and redisplayed.

```
RDG> quiet on
RDG> quiet
quiet = on
RDG>
```

SEE ALSO

rdg(1), status(1)

quit - Exit from rdg debugger program

SYNOPSIS

quit

DESCRIPTION

quit exits from the rdg debugger program and returns the user to the ROM> prompt.

SEE ALSO

rdg(1)

.

rdg - description of the extended ROM resident diagnostics

SYNOPSIS

rdg

DESCRIPTION

rdg is a ROM-resident diagnostics. The test controller provides the commands necessary to randomly select and execute any or all of the available test programs. The operator has control over test execution and can command test programs to loop on error or repeat execution indefinitely.

Command names and abbreviations are not case sensitive.

The acceptable commands follow (bold, uppercase letters represent the abbreviated usage of the command name):

```
?
        Print summary of rdg commands
between Set or display between count
config Display memory configuration
continue
        Set or display continue on error flag
errlim
        Set or display error limit
        Display error count
errors
fbconfig
        Displays the frame buffer configuration
help
        Display command list or information on a specific command
limit
        Display or set memory test limits
loop
        Set or display loop on test flag
menu
        Display listing of the available tests
names
        Enable or disable printing of test names during test exe-
        cution
        Execute next selected test
next
passes
        Display pass count
passlim Set or display pass limit
prompt
        Set or display prompt flags
quiet
         Set or display error message enable flag
quit
        Exit from rdg program
restart Restart execution of selected tests
         Start execution of selected tests
run
status
        Display or reset state of modes, flags and counts
tests
         Select or display tests to be executed
time
         Set a display print time flag
vmeconf Configure VMEbus devices
```

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restart - Restart execution of selected tests

SYNOPSIS

restart

DESCRIPTION

restart causes the current **test**(1) selection to be executed beginning with the first test current test selection. The major difference between **restart** and **run**(1) is that **restart** goes back to the first test in the sequence, while **run** continues execution with the next selected test.

The number of times the test selection is executed depends on the value of the **passlim** (1) *limit*.

EXAMPLE

User input in the example is shown in **boldface** type.

In the following example run was entered to begin test execution. The current test selection were executed until an error was encountered in test 3. **restart** was entered to start the test sequence again from the beginning.

```
RDG> run
Starting Test 1: (testname)
Starting Test 2: (testname)
Starting Test 3: (testname)
Test 3 error: (error message)
RDG> restart
Starting Test 1: (testname)
Starting Test 2: (testname)
Starting Test 3: (testname)
.
.
.
Starting Test n: (testname)
Tests completed: Passes = 1 Errors = 0
Fri Sep 28 16:30:33 1988
RDG>
```

SEE ALSO

next(1), **passlim**(1), **rdg**(1), **run**(1)

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run - Start execution of selected tests

SYNOPSIS

run

DESCRIPTION

run causes the current test (1) selection to be executed. The number of times the test selection is executed depends on the value of the passlim (1) *limit*.

EXAMPLE

User input in the example is shown in **boldface** type.

In the following example run was entered to begin test execution. The current test selection was executed once (passlim = 1) followed by a tests completed message. If passlim's *limit* is set to a value other than one, the complete test sequence would be repeatedly executed until *limit* is reached, at which time the program would return to the RDG> prompt. The test completed message is displayed after each pass.

SEE ALSO

next(1), passlim(1), rdg(1), restart(1)

and the second second

status - Display or reset state of modes, flags, and counts

SYNOPSIS

status [reset] [flags]

DESCRIPTION

status displays the current state of all modes, program flags, and counters. flags resets all the flags, which includes names, continue, loop, and quiet.

OPTION

- **reset** Resets the status of flags, counts, and limits to the default setting. **reset** also resets the test selection back to default values.
- flags Resets the status of flags to the default settings.

EXAMPLE

User input in the example is shown in **boldface** type.

```
RDG> status
Wed Nov 25 12:45:20 1987
Names = on
Continue = off
Loop = off
Quiet = off
Time = off
Pass count = 0
Pass limit = 1
Between count = 1
Error count = 0
Error limit = 0
RDG>
```

SEE ALSO

between (1), continue (1), ecc (1), errlim (1), errors (1), loop (1), names (1), passes (1), passlim (1), quiet (1), rdg (1), time (1)

tests - Select or display tests to be executed

SYNOPSIS

tests [all | test test ... | test:test ...]

DESCRIPTION

tests select the tests for execution by the run(1) command. By default, all tests are selected for execution when the program is initialized.

Single tests or a range of tests may be selected by specifying the test numbers or range of tests number.

OPTIONS

- all Execute all the tests. all can be specified at any time to reselect all tests.
- test Execute specified test. If test is not specified, the tests command displays the current test selection.

EXAMPLES

User input in the examples is shown in **boldface** type.

The following example illustrates how to display the test selection.

RDG> tests selected tests: 1 2 3 4 5 6 7 8 9

RDG>

In the following example, tests 1, 5 and 10 are selected and then displayed.

```
RDG> tests 1 5 9
RDG> tests
selected tests: 1 5 9
RDG>
```

In the following example, tests 8 through 1 are selected and displayed. Note that tests may be selected to run in any order.

```
RDG> tests 8:1
RDG> tests
selected tests: 8 7 6 5 4 3 2 1
RDG>
```

In the following example, all installed tests are selected and displayed.

```
RDG> tests all

RDG> tests

selected tests: 1 2 3 4 5 6 7 8

9

RDG>
```

SEE ALSO

```
next(1), rdg(1), restart(1), run(1)
```

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time - Set or display print time flag

SYNOPSIS

time [on | off]

DESCRIPTION

time sets or displays the print-time flag. If no parameters are specified, time displays the current setting of the print-time flag and the current time and data. The print-time flag controls whether the current time and date is printed when test names are displayed during test execution. The default state of the print-time flag is off (no time printed). If both the names flag and print-time flag are on, the time and date is printed on the line following the test name during test execution.

OPTIONS

- **on** Turns on the print-time flag.
- off Turns off the print-time flag.

EXAMPLES

The following example causes the current print-time flag to be displayed:

```
RDG> time
time = off
Fri Sep 28 14:20:00 1988
RDG>
```

The following example illustrates how the print-time flag is changed and redisplayed.

```
RDG> time on
RDG> time
time = on
Fri Sep 28 14:20:00 1988
RDG>
```

SEE ALSO

names (1), **rdg** (1), **status** (1)

1

NAME

vmeconf - Configure VMEbus devices

SYNOPSIS

vmeconf

DESCRIPTION

vmeconf generates or displays the VMEbus configuration table.

When **rdg** is invoked, it does not ask the user to generate a VMEbus configuration table. Therefore, if the user wishes to run VMEbus tests, this command must be executed first.

vmeconf prompts for all user input. It accepts no options or arguments at the command line.

Currently, vmeconf supports the Ciprico Rimfire, Excelan Ethernet, and Plessy RAM boards.

EXAMPLE

User input in the example is shown in **boldface** type.

The following example shows how **vmeconf** is used to remove an Excelan Ethernet VMEbus board from the configuration, then how the program would be used to put the board back into the configuration table.

```
RDG> vmeconf
```

```
VMEbus Configuration consists of four boards
      (0) Ciprico Rimfire 3500 VMEbus-to-SCSI
                                          Physaddr = 0x85ff5000
            Am = 0x2d \quad Addr = 0x5000
      (1) Excelan Ethernet
            Am = 0x3d Addr = 0xd00000
                                          Physaddr = 0x87d00000
      (2) Plessey RAM (512K)
            Am = 0x3d \qquad Addr = 0x100000
                                          Physaddr = 0x87100000
Do you wish to change this configuration? (y/n) y
Do you want the default configuration? (y/n) n
Do you want to delete any entries? (y/n) y
Entry number to delete (q to quit)? 1
Entry number to delete (q to quit)? q
Do you want to add any entries? (y/n) n
      (0) Ciprico Rimfire 3500 VMEbus-to-SCSI
            Am = 0x2d Addr = 0x5000
                                          Physaddr = 0x85ff5000
      (2) Plessey RAM (512K)
            Am = 0x3d \quad Addr = 0x100000
                                          Physaddr = 0x87100000
Do you wish to change this configuration? (y/n) y
Do you want the default configuration? (y/n) n
Do you want to delete any entries? (y/n) n
Do you want to add any entries? (y/n) y
How many vme boards are to be added? (0-5) 1
Enter information for board 1:
```

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Valid vme board types are: 0: none 1: Ciprico Rimfire 3500 VMEbus-to-SCSI 2: Excelan Ethernet 3: Plessey RAM (512K) Type of board? 2 Valid address modifiers are: 9: extended user data access d: extended supervisor data access 39: standard user data access 3d: standard supervisor data access 29: short user data access 2d: short supervisor data access Address modifier? 3d Address? d00000 VMEbus Configuration consists of 3 boards (0) Ciprico Rimfire 3500 VMEbus-to-SCSI Am = 0x2d Addr = 0x5000 Physaddr = 0x85ff5000 (1) Excelan Ethernet Am = 0x3d Addr = 0xd00000 Physaddr = 0x87d00000(2) Plessey RAM (512K) Am = 0x3d Addr = 0x100000 Physaddr = 0x87100000 Do you wish to change this configuration? (y/n) ${\bf n}$ RDG>

SEE ALSO rdg(1)

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Appendix A: MARCH Algorithm

A.1 Introduction

This appendix explains the way the MARCH pattern algorithm works. The steps follow:

- 1. Every location of the target RAM is written from low address to the high address with the background pattern. This is the first pattern of the initial complement pair (00).
- 2. The low address in the RAM is read and verified to contain the background pattern. If the background pattern is correct, the complement pattern is written to the same address. The location is read again and verified to now contain the complement pattern.
- 3. Step 2 is repeated for all addresses, from low to high. At this point, every location in RAM contains the complement pattern. Once this has completed, the test goes in reverse order from the high address back to the low address. The first read is now verified to contain the complement pattern followed by a write and read of the background pattern.
- 4. This test advances to the next complement pattern pair and repeats the same steps.



Appendix B: Moving Inversions Test Algorithm

B.1 Introduction

This appendix contains a general description of the Moving Inversions Algorithm (MOVI) commonly used to verify the addressing and data integrity of RAM devices. The strengths of this algorithm are its relatively short execution time, functional testing of memory bits, and dynamic tests of best and worst case access times.

In principle, MOVI inverts the data of each address sequentially, thus creating an access time by the jump from one address to another which contains different information. To measure access times, the data at each address is read before and after inversion. This requires three operations on each address: a read, a write, and another read.

The read/write/read operations are performed with both forward and backward (reverse) address sequences, and also with n orders of the address-bit significance (where n is the number of address bits).

A general stepwise description of the MOVI algorithm is presented below:

- 1. The target memory is filled with a background data pattern.
- 2. In the forward direction (from low to high addresses) a target location is read and check for the correct background pattern (this is the 1st read of the forward pass).
- 3. The complement pattern (1's complement of the background pattern) is written to the target location.
- 4. The target location is read and checked for the correct complement pattern (this is the 2nd read of the forward pass).
- 5. Steps 2 through 4 are repeated for all addresses until the high address of the memory has been reached. At this point the memory should be filled with the complement pattern (assuming no errors were encountered).
- 6. In the reverse direction (from high to low address) a target location is read and checked for the correct complement pattern (this is the 1st read of the reverse pass).
- 7. The background pattern (1's complement of the complement pattern) is written to the target location.
- 8. The target location is read and checked for the correct background pattern (this is the 2nd read of the reverse pass).
- 9. Steps 6 through 8 are repeated for all addresses until the low address of memory has been reached. At this point the memory should be filled with the background pattern again (assuming no errors were encountered during the reverse pass).

The steps above implement the first iteration of the MOVI test, where the basic address increment value is 1. Successive iterations use higher address-bit significance up to 2**n where n is the number of involved address bits. This is the same as using a different bit of the address each time as the least significant bit for incrementing through all possible addresses. This has the effect of incrementing through all the addresses by 2's, 4's, 8's, and so on; every address overflow generates and end-around carry, so that all addresses are tested once in each sequence.

The table illustrates the binary address sequences generated by MOVI for and eight location memory:

Forward sequences:

Iteration	0	1	2
	lsb	lsb	lsb
	v	v .	v
	0000	0000	0000
	001 1	010 2	100 4
	010 2	100 4	
	011 3	1106	0011
	100 4		101 5
	101 5	0011	
	1106	011 3	010 2
	1117	101 5	1106
		1117	
			0113
			1117

Reverse sequences:

Iteration	0	1	2
	lsb	lsb	lsb
:			
	v	v	v
·	1117	1117	1117
	1106	101 5	011 3
	101 5	011 3	
	1004	001 1	1106
	011 3		010 2
	010 2	1106	
	001 1	100 4	101 5
	0000	010 2	0011
		0000	
			100 4
			0000

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